

<b>Notice of References Cited</b>	Application/Control No. 10/772,360		Applicant(s)/Patent Under Reexamination FURUKAWA, HITOSHI	
	Examiner Mark R. Milia		Art Unit 2625	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,131,124	10-2006	Hanyu, Yoshiaki	717/178
*	B	US-2004/0068548	04-2004	Sugita, Takatoshi	709/208
*	C	US-2003/0093612	05-2003	Ootani et al.	711/103
*	D	US-2003/0035132	02-2003	Tomita et al.	358/1.14
*	E	US-6,341,239	01-2002	Hayashi et al.	700/79
*	F	US-2002/0181289	12-2002	Matsubara et al.	365/185.33
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.